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IC FABRICATION

MVR Shashi - com

* DOPING:

- i) Diffusion
- ii) Ion Implantation
- iii) Epitaxy

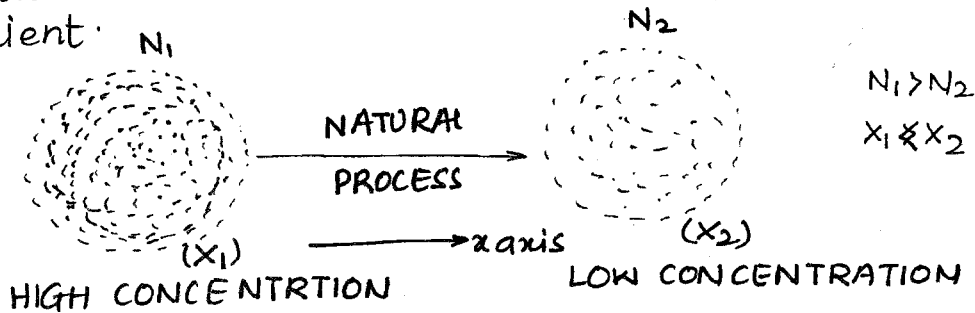
* NPTEL → Prof. Nandita Dasgupta.
(VLSI Fabrication)

* SK Gandhi

* Oxidation, Ion Implantation
diffusion → numericals.

i) DIFFUSION:

* Diffusion means movement of material under concentration gradient.



* As

$$J = -D \frac{dn}{dx} \leftarrow \text{FICKS 1st Law of Diffusion.}$$

Hence -ve sign.

D = diffusion const.

J = Flux (always +ve). (we always say that Flux is +ve).

$\frac{dn}{dx}$ = Concentration gradient

$$\frac{dN}{dx} = \frac{N_2 - N_1}{x_2 - x_1} \leftarrow \text{-ve quantity}$$

* FICKS 2nd LAW OF DIFFUSION:

* FICKS 2nd law of diffusion states that:

$$\nabla \cdot J = -\frac{\partial n}{\partial t}$$

$$\nabla = i \frac{\partial}{\partial x} + j \frac{\partial}{\partial y} + k \frac{\partial}{\partial z}$$

* For one dimension we get:

$$\frac{\partial J}{\partial x} = -\frac{\partial n}{\partial t}$$

$$J = -D \frac{\partial N}{\partial x} \quad \dots (i)$$

$$\frac{\partial J}{\partial x} = - \frac{\partial N}{\partial t} \quad \dots (ii)$$

diff. eqn (i) wrt x we get:-

$$\frac{\partial J}{\partial x} = -D \frac{\partial^2 N}{\partial x^2}$$

from eqn (ii) we get:-

$$\frac{-\partial N}{\partial t} = -D \frac{\partial^2 N}{\partial x^2}$$

$$\boxed{\frac{D \partial^2 N}{\partial x^2} = \frac{\partial N}{\partial t}} \leftarrow \text{Wave Equation}$$

N : Concentration.

x : space.

t : time.

* N is a funcⁿ of Both space and time.

$$\boxed{N = f(x, t)}$$

* TYPES OF DIFFUSION:

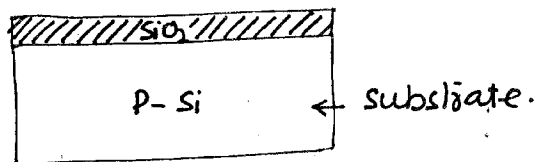
i) Predeposition / Infinite Source Diffusion.

ii) Drive in / Limited source diffusion.

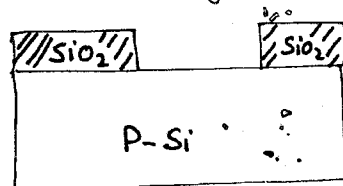
i) Predeposition / Infinite Source Diffusion:

a) Take P substrate.

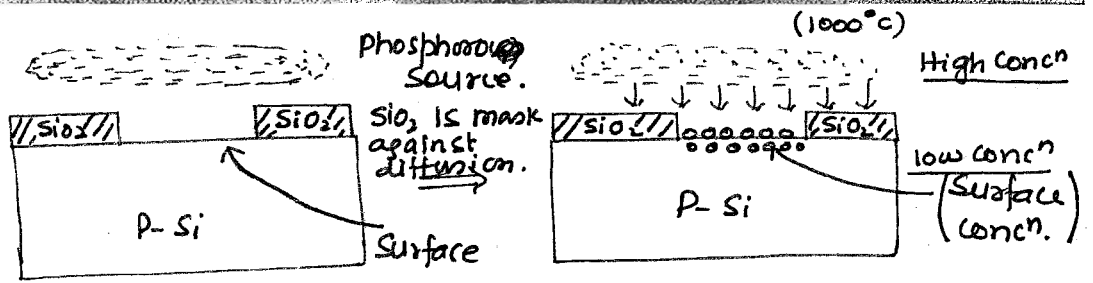
Diode Formation



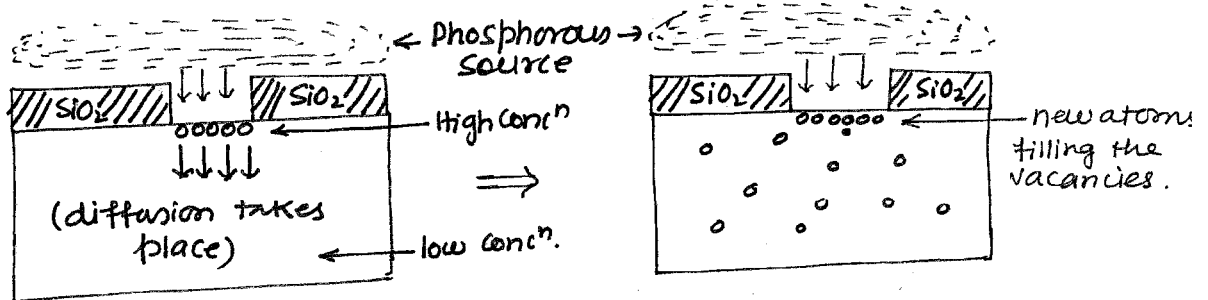
b) open a window using lithography + Etching



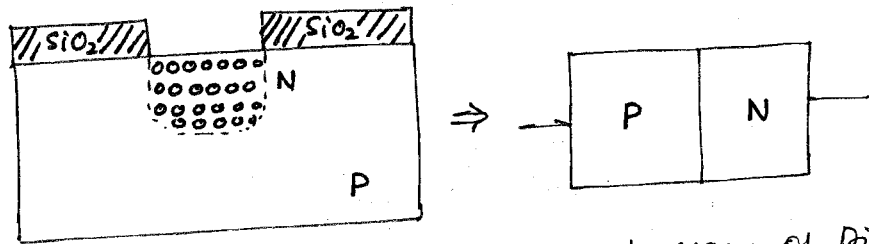
3)



4)



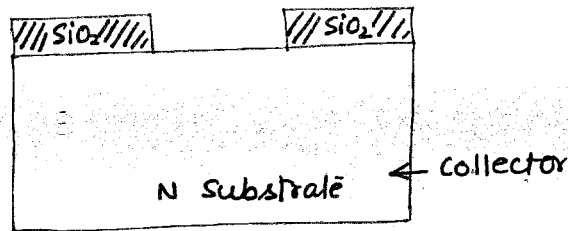
5) Finally,



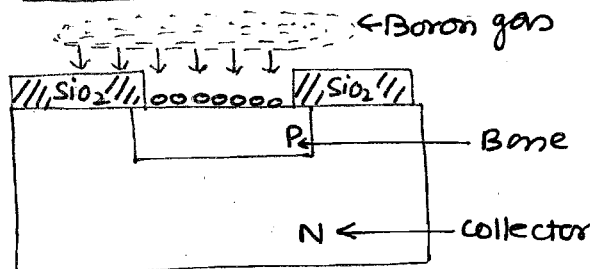
* Diffusion occurs at $1000^\circ C$ and to stop the process of diffusion decrease the temperature.

* BJT FORMATION (NPN):

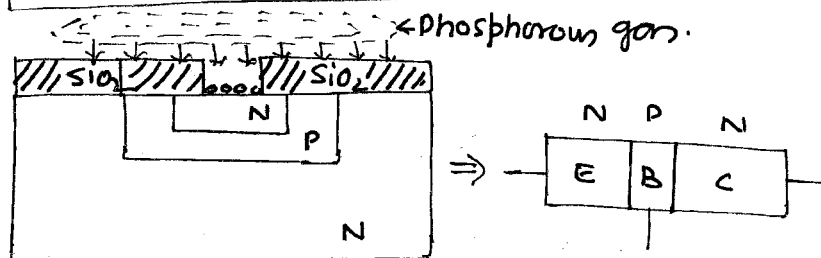
1) Take N substrate



2)



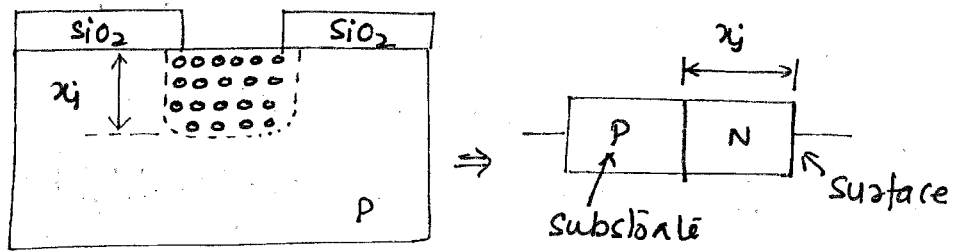
3)



Note:

* Contacts are also to be connected.

* Parameters of Diffusion:
 → Junction Depth.
 → Doping Profile.
 → Surface concentration.

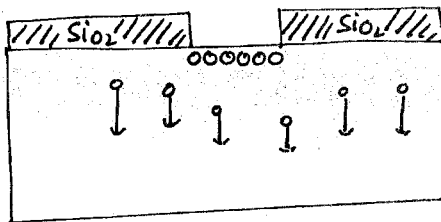
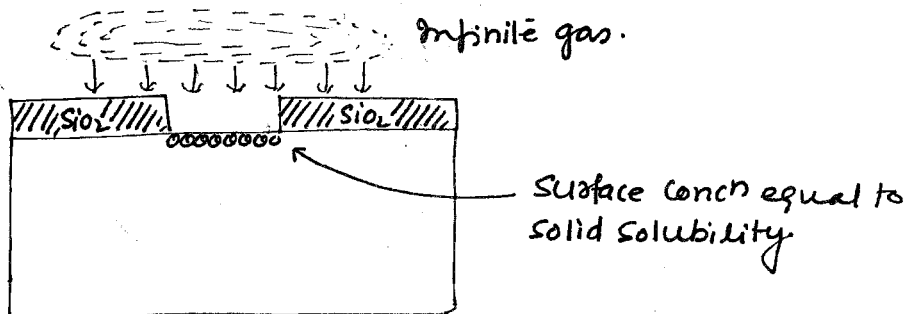


x_j : Junction Depth is distance from surface where junction forms.

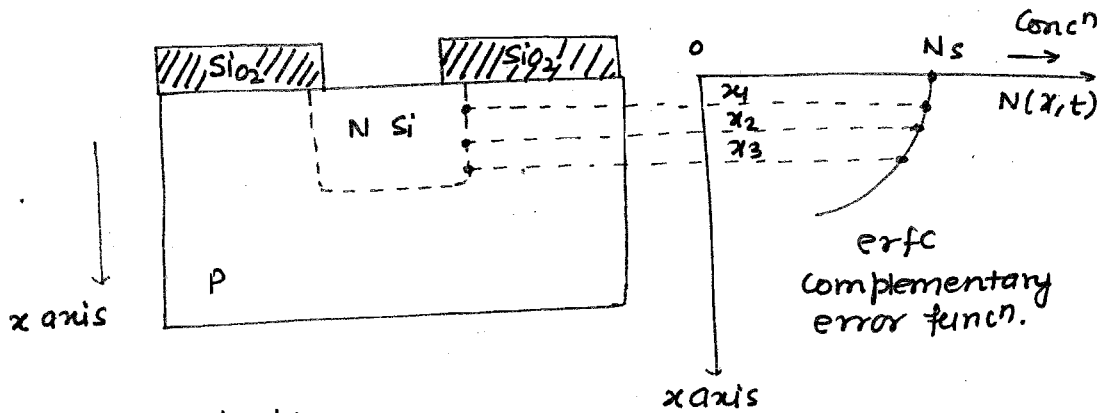
* Surface Concⁿ in Predeposition:

* Solubility is a funcⁿ of Temp.

* Surface concⁿ is always constant i.e. the vacancies created at surface remain const.



* DOPING PROFILE:



We know that:

$$\frac{D \partial^2 N}{\partial x^2} = \frac{\partial N}{\partial t} \leftarrow \text{Partial differential equation.}$$

$$N(x,t) \Big|_{x=\infty} = 0$$

$$N(x,t) \Big|_{x=0} = N_s \leftarrow \text{Surface concn.}$$

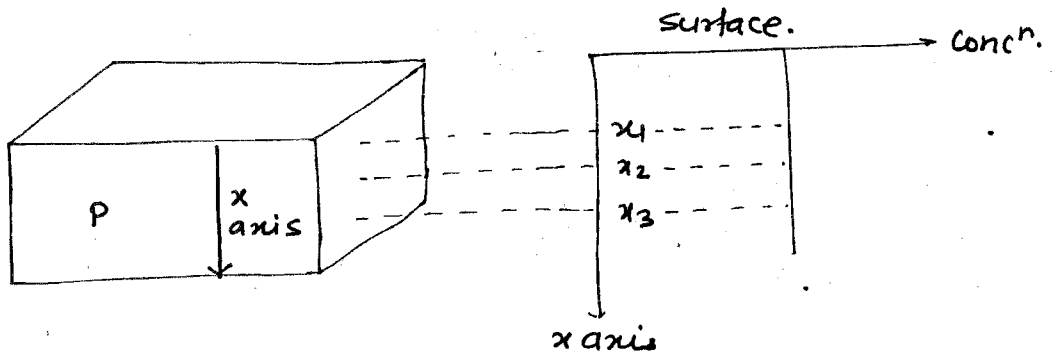
$$N(x,t) \Big|_{t=0} = 0 \leftarrow \text{Boundary conditions}$$

* Solution for the partial differential equation is given as:

$$N(x,t) = N_s \operatorname{erfc} \left(\frac{x}{2\sqrt{Dt}} \right) \quad \boxed{t: \text{time.}}$$

* EPITAXY is method of UNIFORM DOPING:

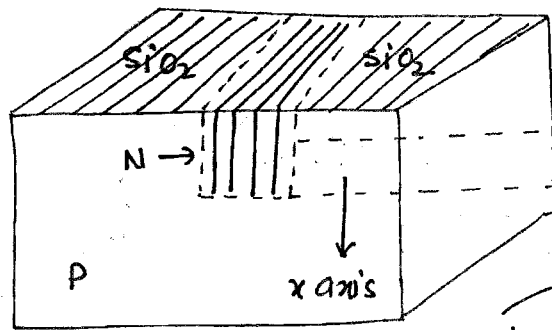
Note:



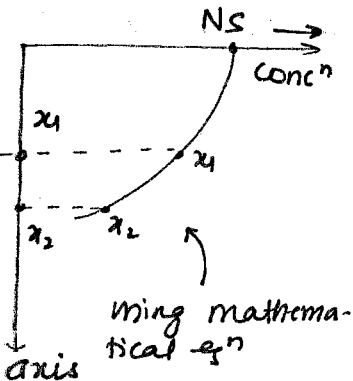
UNIFORM DOPED
SUBSTRATE

Phosphorous →

- * at constant temp.
- * N_s is constant at given temp.

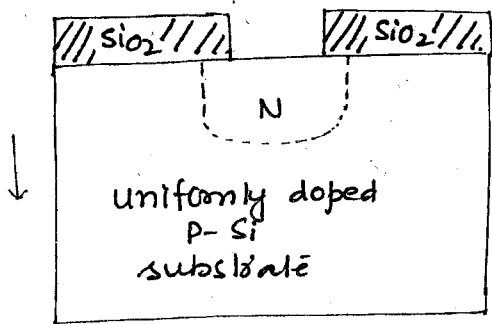


(profile of N type material) (Predeposition case)

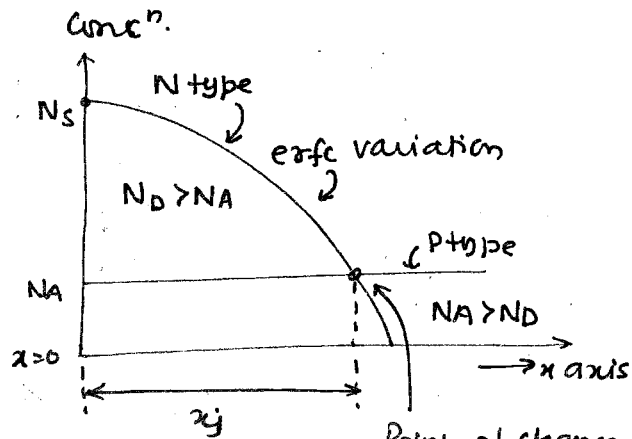


* Junction Depth:

- * Consider a uniformly doped P type substrate.
- * Assume N type diffusion has been done.



N_A : Acceptor concn
 N_D : Donor concn.



Point of change of Dominance.

* Juncⁿ forms when material changes from N type to P type and vice versa.

* At the juncⁿ i.e. $x = x_j$ ← Point of Intersection of Curves.

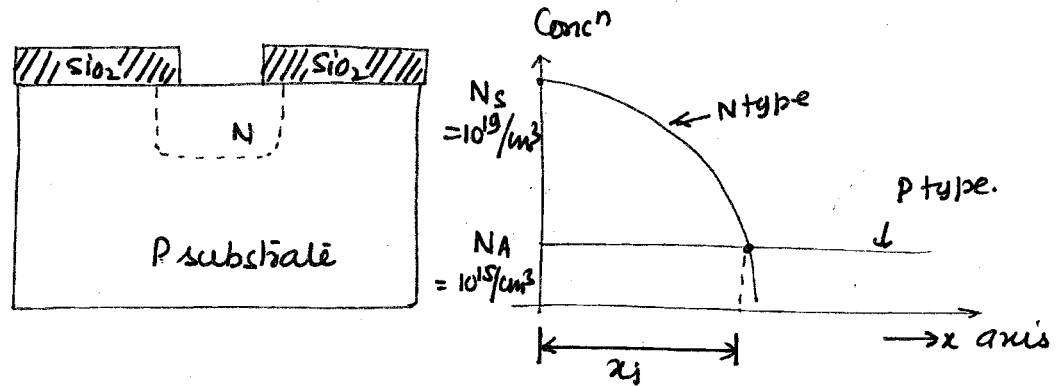
$$N_A = N(x, t)$$

So, $N_A = N_s \operatorname{erfc}\left(\frac{x}{2\sqrt{Dt}}\right) = N(x, t).$

Q1) Phosphorous is diffused into uniformly doped P type substrate with background concⁿ of $10^{15}/\text{cm}^3$ at $T=1100^\circ\text{C}$. The diffusion constant at this temp is $10^{-12}\text{cm}^2/\text{sec}$; solid solubility of Phosphorous and silicon is $10^{19}/\text{cm}^3$ at 1100°C . Assume predeposition time of 1 hour. Find the junction depth? erfc of $2.75 = 10^{-4}$

$$\text{erfc}(2.75) = 10^{-4}$$

Soln:



* At the junction:

$$N_A = N(x, t) = N_s \text{erfc}\left(\frac{x_j}{2\sqrt{Dt}}\right)$$

$$10^{15} = 10^{19} \text{erfc}\left(\frac{x_j}{2\sqrt{Dt}}\right)$$

$$10^{-4} = \text{erfc}\left(\frac{x_j}{2\sqrt{Dt}}\right)$$

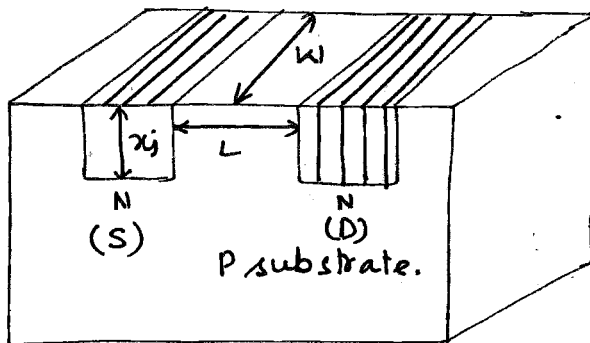
$$\text{So, } 2.75 = \frac{x_j}{2\sqrt{Dt}}$$

$$\text{or } x_j = 2.75 \times 2 \times \sqrt{10^{-12}\text{cm}^2/\text{sec} \times 3600\text{sec}}$$

$$x_j = 3.3\mu\text{m}$$

Note:

- L: channel length.
- w: channel width
- x_j : junction depth.



(N MOS)

Note:

- * Junction depth is decided during diffusion process
- * w/L Ratio decided during lithography process. (~~lithography~~)
- * x_j is important parameter in MOSFET fabrication.

Q2) Boron is diffused into an n type sc with back ground concn of $10^{14}/\text{cm}^3$. The predeposition is carried out for 2 hrs. Assume diffusion const of 5×10^{-13} ; solid solubility of $10^{20}/\text{cm}^3$. Find the junction depth.

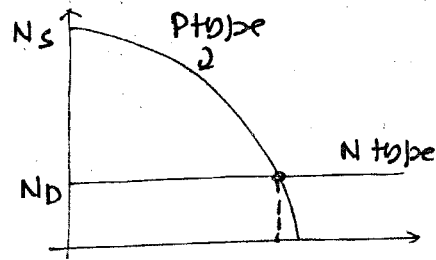
$$\text{erfc}(3.45) = 10^{-6}$$

Soln:

$$N_s \text{erfc}\left(\frac{x_j}{2\sqrt{Dt}}\right) = N_D$$

$$10^{20} = 10^{20} \text{erfc}\left(\frac{x_j}{2\sqrt{Dt}}\right)$$

$$10^{-6} = \text{erfc}\left(\frac{x_j}{2\sqrt{Dt}}\right)$$



So, $\frac{x_j}{2\sqrt{Dt}} = 3.45$ ***
 \leftarrow in Prelims.

$$x_j = 2 \times 3.45 \times \sqrt{5 \times 10^{-13} \times 2 \times 3600}$$

$$x_j = 60 \times 10^{-6} \times 2 \times 3.45$$

$$x_j = 414 \times 10^{-6} \text{ cm.}$$

$$= 4.14 \mu\text{m.}$$

Note (Prelims) :

$$\text{erfc}(3.45) = 10^{-6} \Rightarrow \text{erfc}^{-1}(10^{-6}) = 3.45$$

$$\text{erfc}(2.75) = 10^{-4} \Rightarrow \text{erfc}^{-1}(10^{-4}) = 2.75$$

} Constant Value.

Now,

$$N_A = N_s \text{erfc}\left(\frac{x_j}{2\sqrt{Dt}}\right)$$

$$\left(\frac{N_A}{N_s}\right) = \text{erfc}\left(\frac{x_j}{2\sqrt{Dt}}\right)$$

$$\text{erfc}^{-1}\left(\frac{N_A}{N_s}\right) = \text{constant} = \frac{x_j}{2\sqrt{Dt}} = K.$$

$$\text{So, } x_j = 2\sqrt{Dt} \times K.$$

$$x_j \propto \sqrt{t}$$